

Syft European User Meeting | 19-20 October 2015

held in conjunction with 

LOCATION: Down Hall, near London Stansted Airport, United Kingdom

MONDAY 19 OCTOBER

- 5.00pm **Welcome and introductions, mixer**
- 5.30pm **Introduction to Syft Technologies and SIFT-MS**
- 6.00pm **Instrument demonstrations**
- 7.00pm **Dinner**

TUESDAY 20 OCTOBER

- 9.00am **Welcome and overview of the day**
- 9.05am **The science and applications of SIFT-MS**
- 10.00am **New developments from Syft Technologies**
- 10.30am **Tea/coffee break**
- 11.00am **Plenary lecture: Sheryl Barringer, The Ohio State University, USA**
- 11.35am **Invited speaker: Jihoon Lee, AT-Frontier, South Korea**
- 12.00pm **Lunch**
- 1.00pm **Invited speaker: Joeri Vercammen, Interscience / ISX, Netherlands/Belgium**
- 1.25pm **Invited speaker: Jessika De Clippeleer, KaHo, Belgium**
- 1.50pm **Invited speaker: Malli Motapothula, National University of Singapore, Singapore**
- 2.15pm **Software demonstration**
- 3.00pm **Tea/coffee break**
- 3.30pm **Syft presentations**
 - Vehicle interior air quality analysis
 - Semiconductor fab air quality testing
- 4.15pm **Meeting reflection and close**
- 4.30pm **Close of Meeting**

For further information

Please email Sue Roach at Anatune (susan.roach@anatune.co.uk) or Vaughan Langford at Syft Technologies (vaughan.langford@syft.com)